

Supporting information for p-type Cr-doped TiO₂ photo-electrode for photo-reduction

*Junyu Cao*¹, *Yuanjian Zhang*², *Lequan Liu*^{1,3}, *Jinhua Ye*^{1,3,4,*}

1. Catalytic Materials Group, Environmental Remediation Materials Unit, National Institute for Materials Science (NIMS), 1-1 Namiki, Tsukuba, Ibaraki, Japan
2. School of Chemistry and Chemical Engineering, Southeast University, Nanjing 211189, P. R. China
3. International Center for Materials Nanoarchitectonics, National Institute for Materials Science (NIMS), 1-2-1 Sengen, Tsukuba, Ibaraki, Japan
4. TU-NIMS Joint Research Center, School of Materials Science and Engineering, Tianjin University, 92 Weijin Road, Nankai District, Tianjin, P. R. China

Experimental

Cr-doped TiO₂ photo-electrode and local Cr-doped TiO₂ photo-electrode were fabricated using pulsed laser deposition (PLD) method. Cr-doped TiO₂ pellet (atomic ratio Cr: Ti=6: 100) and pure TiO₂ pellet were utilized as the targets. Sn doped Indium-oxide-coated glass sheet (ITO) were selected as the substrates. The pellets and ITO were set in the PLD machine (ST-PLD; Pascal co., Japan), and the distance between the pellet and the ITO was set to be 5 cm. After that, the film-preparation chamber of the PLD machine was evacuated to 0.001 Pa, and then pure O₂ was introduced into the chamber until the pressure became 4 Pa. After ITO substrate was heated to 550 °C, the target was irradiated by the laser pulse (60 mJ per pulse; 355 nm in wavelength) emitted from a Nd:YAG laser. After the deposition, the substrate temperature (550 °C) was still kept for 1 h in the presence of O₂ (9.6×10⁴ Pa) for the post-heat treatment of the samples.

Cr-doped TiO₂ thin films were fabricated by irradiating Cr-doped TiO₂ target for 1 h. Local Cr-doped TiO₂ thin films were fabricated by irradiating Cr-doped TiO₂ target for 40 min firstly and then irradiating TiO₂ target for 20 min.

After the pulsed laser deposition process, Pt was loaded by using photo-deposition method. The local Cr-doped TiO₂ thin films were immersed in 0.5 wt% H₂PtCl₆ aqueous solution under the light irradiation condition for 1 h. After the photo-deposition, the samples were heated at 400 °C for 1 h.

Chemical compositions of the prepared photo-electrodes were evaluated with a transmission electron microscope (2100F, JEOL Co., Japan), field-emission scanning electron microscope (JSM-6701F, JEOL Co., Japan) and XPS. Photocurrent densities were measured with an electrochemical station (ALS/CH model 650A) using three-electrode mode. Platinum and Ag/AgCl electrode were used as the counter electrode and reference electrode, respectively. In the photoelectrochemical measurement, the photo-electrodes were illuminated with the light from the side of the electrolyte/film interface in aqueous Na₂SO₄ solution (0.1 M) through a quartz window. AM 1.5 Solar simulator (PEC-L01, Pecell Co., Japan) was utilized as the light sources.

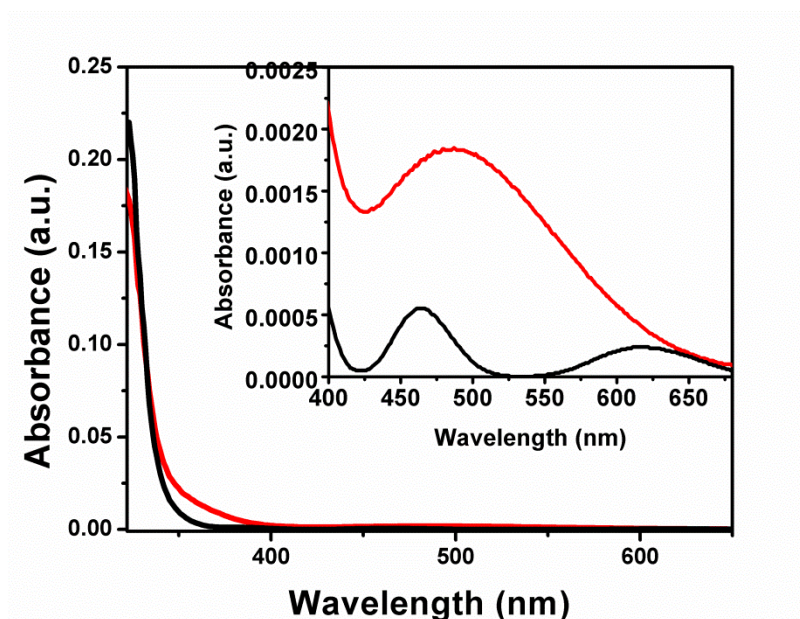


Fig.S1 UV-vis spectra of uniformly Cr doped TiO₂ thin film and TiO₂ thin film.

Fig. 1 shows the UV-vis spectra of the as-prepared TiO₂ and uniformly Cr-doped TiO₂ photo-electrodes by PLD method. The absorbance of uniformly Cr-doped TiO₂ photo-electrode exhibits an obvious shift towards longer wavelength, comparing with that of the TiO₂ photo-electrode. The inset of **Fig. 1** shows that uniformly Cr-doped TiO₂ can absorb the visible light with the wavelength shorter than about 650 nm. Here, the oscillation of the TiO₂ photo-electrode absorbance curve in the region from 400 nm to 680 nm should be due to the interference effect caused by the TiO₂ layer, not by the light absorbance of TiO₂.

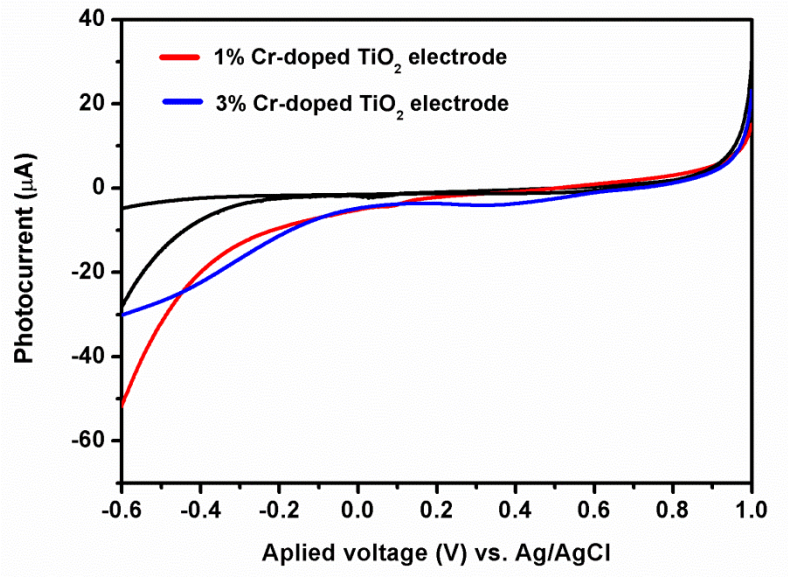


Fig. S2 The photocurrent vs. potential curve of 1% and 3% Cr-doped TiO₂ electrode.

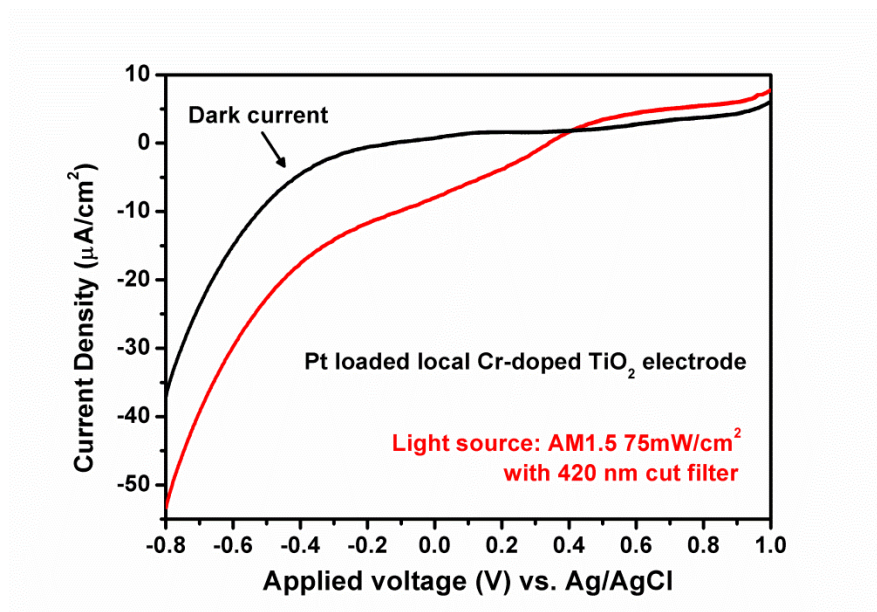


Fig.S3 I-V curves of inner Cr-doped TiO₂ thin film with Pt-loading under visible light.

Inner Cr-doped TiO₂ photo-electrode with Pt-loading exhibited obvious visible light response. As showed in **Fig. 2**, a negative photocurrent density could be observed under AM1.5 solar simulation with 420 nm cutoff filter.

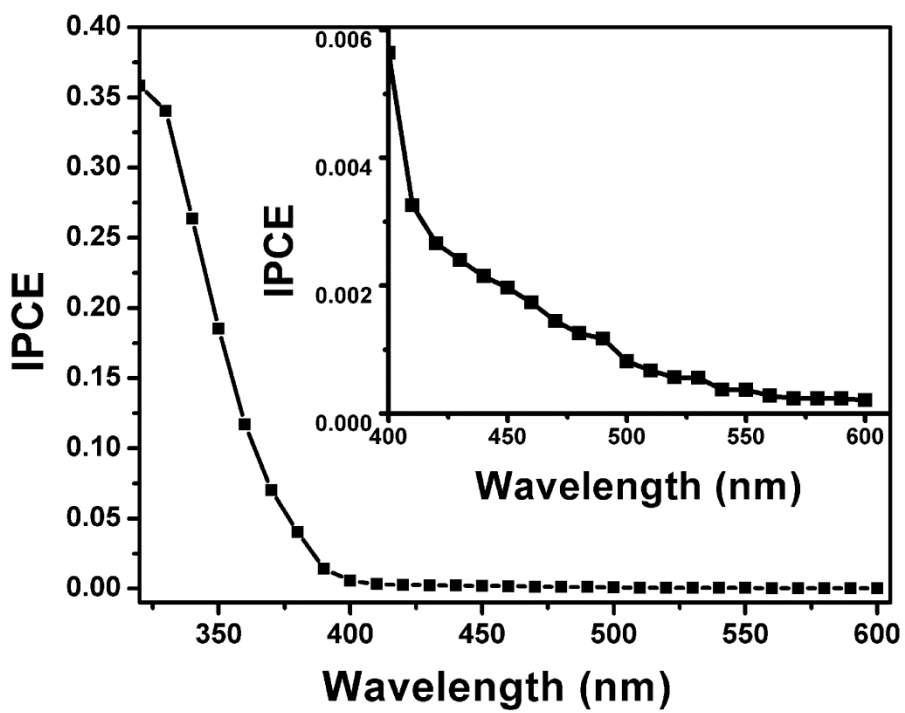


Fig.S4 IPCE of inner Cr-doped TiO₂ thin film with Pt-loading at -0.2 V vs. Ag/AgCl/